

DESCRIPTION			
Insulated Metal Substrate (IMS), based aluminium clad with ED copper foil on the opposite side. It is designed for the reliable thermal dissipation of circuitry. A proprietary formulated reinforced-polymer-ceramic bonding layer with a high thermal conductivity and dielectric strength allows us to guarantee thermal endurance.			
The material is supplied with a film on the aluminium side to protect it against wet PCB processes.			
ROHS compliance directive 2002/95/EC and REACH N° 1907/2006			
STANDARD CONSTRUCTIONS			
Aluminium thickness, µm (in)	1000 (0,0394) - 1500 (0,059)	Aluminium Alloy / Treat	5052
Insulation thickness	100 (4 mils)	Dielectric thickness tolerance	+ 10 µm (+/- 0,4 mils)
ED copper thickness, µm (in)	35 (1oz) – 70 (2oz)		
UL Approved , QMST2 File: E47820			

(1) Electrical proof test. Sampling verification at 1000 V_{dc}

PROPERTIES (*) 1500 µm Al / 100 µm dielectric / 70 µm Cu	TEST METHOD	UNITS	TYPICAL VALUES	Guaranteed values
Time to blister at 288°C, floating on solder (50 x 50 mm)	IEC-61189	Sec	>120	>60
Copper Peel strength, after heat shock 20 sec/288°C	IPC-TM 650-2.4.8	N/mm (Lb/in)	2,3 (13,1)	>1,8 (>10,3)
Dielectric breakdown voltage, AC (2)	IPC-TM 650-2.5.6.3	kV	5	4,5
Proof Test, DC (1)	--	V	1000	1000
Thermal conductivity (dielectric layer) (2)	ASTM-D 5470	W/mK (W/inK)	1,30 (0,032)	1,30 (0,032)
Thermal conductivity (Copper+dielectric+aluminium) (3)	ASTM-D 5470	W/mK (W/inK)	18,9	18,9
Thermal conductivity (dielectric layer) (2)	ASA-7540	W/mK (W/inK)	2.0 (0.049)	2.0 (0.049)
Thermal impedance (dielectric layer)	ASTM-D 5470	Kcm ² /W (Kin ² /W)	0,77 (0,12)	0,77 (0,12)
Surface resistance after damp heat and recovery	IEC-61189	MΩ	10 ⁵	10 ⁵
Volume resistivity after damp heat and recovery	IEC-61189	MΩm	10 ⁴	10 ⁴
Relative permittivity after damp heat and recovery, 10 kHz	IEC-61189	-	4,5	4,5
Dissipation factor after damp heat and recovery 10 kHz	IEC-61189	-	0,02	0,02
Comparative tracking index (CTI)	IEC-61112	V	600	>550
Permittivity	--	pF/m (pF/in)	6,7 (39,4)	6,7 (39,4)
Flammability, according UL-94, class	UL-94	Class	V-0	V-0
Glass transition temperature of dielectric layer (by TMA)	IPC-TM 650-2.4.24	°C	120	120
Maximum operating temperature	--	°C	130	130

(*) Values or parameters measured with a destructive method or limited size for the test sample must be considered as a representative values, and not as guaranteed values. They are not guaranteed over 100% of the material.

- (2) **Dielectric Breakdown test**, test is a material destructive laboratory test. It is performed according the IPC-TM-650 part 2.5.6.3., by raising AC voltage until electric failure on a relatively small surface area of the dielectric layer using metal electrodes. Values should be taken as a material reference, and not as guaranteed values.
- (3) **Thermal conductivity** of the full stack of IMS: copper 70mic + dielectric 100 micron (4 mils) + Aluminium 1,5mm (0,059")

AVAILABILITY	
STANDARD SHEET SIZES mm. (in)	1035x1235 (40,7x48,6)
Tolerance	+5/-0 mm (0,2 in)
Squareness	3 mm (0,11 in) max., as differential between diagonal measurements.
Standard size tolerance in panels	+/- 0,3 mm. (0,0118 in)

The data is based on typical values of standard production and should be considered as general information. Our company reserves the right to future changes. It is the responsibility of the user to ensure that the product complies with his requirements.